INSPECTION

INSTALLED CENTRAL OFFICE EQUIPMENT

CONNECTING AND SOLDERING

DETAILED INFORMATION

EQUIPMENT DESIGN REQUIREMENTS

COMMON SYSTEMS

TABLE 800-668-182, Issue 4-D

Lot Range (See Note 1)		B	C	D	E	F	G	H	I	J	K	L
Lot Size (Number of Soldered Connections in Thousands)		4 8	8 15	15 36	36 78	78 140	140 250	250 500	500 1000	1000 2000	2000 3000	3000 4000
Sample Size (Thousand of Connections)		3	6	8	10	12	15	20	40	70	140	200
Inspection Item (See Note 4) (For Requirements refer to Bell System Practices Section 800-612-154, Note 5.)	Basis	Allowable Defect Number										
		AN	AN	AN	AN	AN	AN	AN	AN	AN	AN	AN
1. Security of Connections (See Note 2)	Connection	1	2	3	4	5	7	10	22	40	85	124
2. Clearance (See Note 3)	"	2	3	4	6	8	11	15	32	59	124	183

Note 1: Lots of from 1 to 4000 connections, Lot Range A, shall be inspected completely.

Note 2: Spottiness conditions with respect to insecure connections are usually confined to a particular type of terminal such as the notched or drilled terminal or to particular equipment groups. Special spottiness tests for insecure connections shall therefore be made as follows. For those inspection lots comprising soldered connections or more than one type such as terminal strips, relays, etc, or from more than one equipment group, prior to determining whether the "AN" for connections secure has been exceeded, a spottiness test for this inspection item shall be applied to each "type of terminal" subsample and to each equipment group subsample in which insecure connections are found. The respective sublot is considered to be spotty if more than one defect per thousand connections is found in the corresponding subsample. Each "type of terminal" sublot and each equipment group sublot for which the spottiness limit is exceeded in the corresponding subsample may be treated as a separate lot and inspected completely for this inspection item. When subsamples from the spotty sublots in any inspection lot total more than 2000 connections, the AN for the original sample will no longer apply and a new AN must be determined for a sample equal to the original sample reduced by the number of connections in the subsample from these spotty sublots. The new AN will be that specified in the table for the sample size nearest to this remaining portion of the original sample.

Note 3: Causes of failure to meet the requirement for clearance between terminals are often of such a nature that more than two of the terminals on a single relay, single key, etc, are affected. Clearance defects will be counted on the basis of the connection as indicated in the table except under the following conditions. Where more than one clearance defect occurs on a single relay, a single 244 (well type), 223 or 700 type terminal strip, a single individually mounted jack or a single key, only one clearance defect for each such individual apparatus unit shall be counted in determining the number of defects chargeable to the sample for this inspection item.

Note 4: No specific inspection for broken or weak wires (skinners) is regularly required, but if the number of broken wires observed incidental to the inspection for loose connections exceeds 0.5% of the connections inspected, the condition shall be reported for special consideration. This consideration will determine the advisability of eliminating the condition by further inspection or in the course of subsequent testing operations. Also, if failure to meet the requirements for the condition of soldering other than that for "Security of Connections" and "Clearance" occur frequently, such as excessive solder, unsightly flux, excess wire, etc, the condition shall be reported for special consideration relative to the corrective measures to be employed. (Refer to General Procedure Section.)

Defects found under the above conditions shall be reported separately from those for the inspection items of the table.

Note 5: Requirements of BSP Section 800-612-154 for which no corresponding inspection items are provided in this section shall be checked for the inspection of wiring.

Note 6: For detailed explanation and use of table refer to Bell System Practices Section 800-668-180.